

**Search Notes**

Application/Control No.

10/784,705

Examiner

Son T. Dinh

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2824

**SEARCHED**

Class	Subclass	Date	Examiner
365	148	11/28/2005	SD
365	189.11	11/28/2005	SD
365	100	11/28/2005	SD
365	225.7	11/28/2005	SD

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR